

<b>Notice of References Cited</b>	Application/Control No. 10/749,098	Applicant(s)/Patent Under Reexamination HAYASHI, KENICHI	
	Examiner <i>MC 11/11/05</i> Michelle R. Connelly-Cushwa	Art Unit 2874	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,396,434 A	03-1995	Oyama et al.	700/193
*	B	US-2005/0181527 A1	08-2005	Ohno et al.	438/033
*	C	US-5,740,081 A	04-1998	Suzuki, Ryuji	702/94
*	D	US-2001/0030937 A1	10-2001	Sakamoto et al.	369/277
*	E	US-2002/0093906 A1	07-2002	Deno et al.	369/275.1
*	F	US-2003/0053407 A1	03-2003	Hirokane et al.	369/275.4
*	G	US-5,448,551 A	09-1995	Miyagawa et al.	369/275.1
*	H	US-6,486,965 B1	11-2002	Kim, Hyung-Sik	356/626
*	I	US-5,713,253 A	02-1998	Date et al.	82/1.11
*	J	US-6,301,520 B1	10-2001	Hayashi, Hideki	700/193
*	K	US-3,719,462 A	03-1973	Andreatch, P. et al.	65/30.1
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 02297732 A	12-1990	Japan	HANEDA, NORIHISA	G11B 07/24
	O	JP 07006412 A	01-1995	Japan	YANAI et al.	G11B 07/26
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.